

CY7C1011CV33

2-Mbit (128K x 16) Static RAM

Features

- Temperature ranges
 Industrial: -40°C to 85°C
 Automotive-A: -40°C to 85°C
 Automotive-E: -40°C to 125°C
- Pin and function compatible with CY7C1011BV33
- High speed
- □ t_{AA} = 10 ns (Industrial and Automotive-A) □ t_{AA} = 12 ns (Automotive-E)
- Low active power
 360 mW (max) (Industrial and Automotive-A)
- Data Retention at 2.0
- Automatic power down when deselected
- Independent control of upper and lower bits
- Easy memory expansion with CE and OE features
- Available in Pb-free 44-pin TSOP II, 44-pin TQFP and non Pb-free 48-Ball VFBGA packages

Functional Description

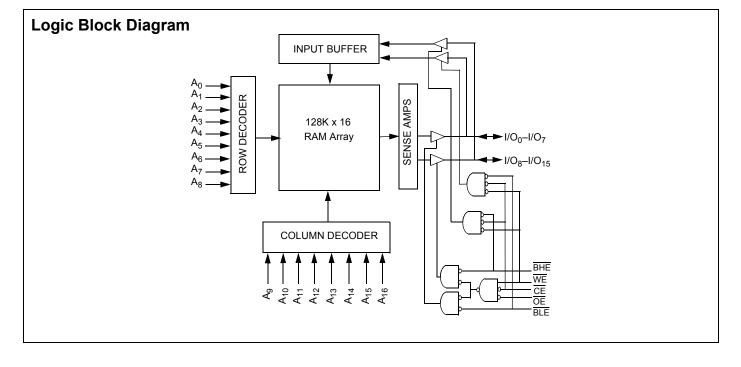
The CY7C1011CV33 is a high performance CMOS static RAM organized as 131,072 words by 16 bits. This device has an automatic power down feature that significantly reduces power consumption when deselected.

<u>To write to the device, take Chip Enable (\overline{CE}) and Write Enable (WE) inputs LOW. If Byte Low Enable (BLE) is LOW, then data from I/O pins (I/O₀ through I/O₇), is written into the location specified <u>on</u> the address pins (A₀ through A₁₆). If Byte High Enable (BHE) is LOW, then data from I/O pins (I/O₈ through I/O₁₅) is written into the location specified on the address pins (A₀ through A₁₆).</u>

To read <u>from</u> the device, take Chip Enable ($\overline{\text{CE}}$) and Output Enable ($\overline{\text{OE}}$) LOW while forcing the Write Enable (WE) HIGH. If Byte Low Enable (BLE) is LOW, then data from the memory location specified by the address pins appear on I/O₀ to I/O₇. If Byte High Enable (BHE) is LOW, then data from memory appears on I/O₈ to I/O₁₅. For more information, see the "Truth Table" on page 9 for a complete description of Read and Write modes.

The input and output pins (I/O₀ through I/O₁₅) are placed in a high impedance state when <u>the</u> device is des<u>elected</u> (\overline{CE} HIGH), the outputs are disabled (\overline{OE} HIGH), the BHE and <u>BLE</u> are disabled (BHE, BLE HIGH), or during a write operation (\overline{CE} LOW and \overline{WE} LOW).

For best practice recommendations, refer to the Cypress application note AN1064, SRAM System Guidelines.



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San Jose, CA 95134-1709 • 408-943-2600 Revised March 24, 2010





Pin Configuration

Figure 1. 44-Pin TSOP II [1]

			-	
A ₄ _	0 1	44		A_5
A ₃ 🗆	2	43		A ₆
A_2	3	42		A ₇
$A_1 \square$	4	41		OE
A ₀	5	40		BHE
CE	6	39	F	BLE
I/O ₀	7	38	F	I/O ₁₅
I/0 ₁ □	8	37		I/O ₁₄
I/O ₂ □	9	36	F	I/O ₁₃
1/0 ₃	10	35	F	I/O ₁₂
Vccັ⊑	11	34		V _{SS}
V _{SS}	12	33		V _{CC}
I/O ₄	13	32		I/O ₁₁
I/O ₅	14	31		I/O ₁₀
I/O ₆	15	30		I/O ₉
I/O7	16	29		I/O ₈
WE	17	28		NC
A ₁₆	18	27		A ₈
A ₁₅	19	26		A ₉
A ₁₄	20	25		A ₁₀
A ₁₃	21	24		A ₁₁
A ₁₂ _	22	23	Р	NC



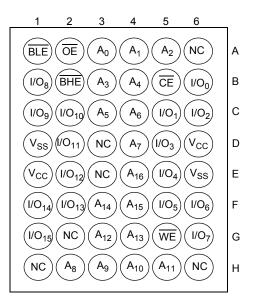
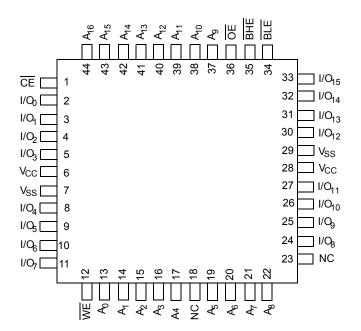


Figure 3. 44-Pin TQFP



Note 1. NC pins are not connected on the die.

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Selection Guide

Description	-10	-12	Unit	
Maximum Access Time	10	12	ns	
Maximum Operating Current	Industrial	100	95	mA
	Automotive-A	100		mA
	Automotive-E		120	mA
Maximum CMOS Standby Current	Industrial	10	10	mA
	Automotive-A	10		mA
	Automotive-E		15	mA



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage Temperature65°C to +150°C
Ambient Temperature with Power Applied –55°C to +125°C
Supply Voltage on V_{CC} Relative to $GND^{[2]}0.5V$ to +4.6V
DC Voltage Applied to Outputs in High Z State ^[2] 0.5V to V_{CC} +0.5V DC Input Voltage ^[2] 0.5V to V_{CC} +0.5V

Current into Outputs (LOW)	20 mA
Static Discharge Voltage (MIL-STD-883, Method 3015)	>2001V
Latch Up Current	>200 mA

Operating Range

Range	Ambient Temperature (T _A)	V _{cc}
Industrial	–40°C to +85°C	$3.3V\pm10\%$
Automotive-A	–40°C to +85°C	
Automotive -E	–40°C to +125°C	

Electrical Characteristics

Over the Operating Range

Deveneter	Description	Test Conditions			-10		-12	
Parameter	Description				Max	Min	Max	Unit
V _{OH}	Output HIGH Voltage	V _{CC} = Min, I _{OH} = -4.0 mA		2.4		2.4		V
V _{OL}	Output LOW Voltage	V _{CC} = Min, I _{OL} = 8.0 mA			0.4		0.4	V
V _{IH}	Input HIGH Voltage			2.0	V _{CC} + 0.3	2.0	V _{CC} + 0.3	V
V _{IL}	Input LOW Voltage ^[2]			-0.3	0.8	-0.3	0.8	V
I _{IX}	Input Leakage	$GND \le V_I \le V_{CC}$	Industrial	-1	+1	-1	+1	μA
	Current		Automotive-A	-1	+1			
			Automotive -E			-20	+20	
I _{OZ}	Output Leakage Current	$GND \le V_I \le V_{CC},$ Output disabled	Industrial	-1	+1	-1	+1	μA
			Automotive-A	-1	+1			
			Automotive -E			-20	+20	
I _{CC}	V _{CC} Operating Supply Current	$V_{CC} = Max, I_{OUT} = 0 mA,$ f = f _{MAX} = 1/t _{RC}	Industrial		100		95	mA
			Automotive-A		100			
			Automotive -E				120	
I _{SB1}	Automatic CE Power Down	Max V _{CC} , CE ≥ V _{IH}	Industrial		40		40	mA
	Current —TTL Inputs	$V_{IN} \ge V_{IH}$ or $V_{IN} \le V_{IL}$, f = f _{MAX}	Automotive-A		40			
			Automotive -E				45	
I _{SB2}	Automatic CE Power Down	Max V_{CC} , $\overline{CE} \ge V_{CC} - 0.3V$,	Industrial		10		10	mA
	Current — CMOS Inputs	$V_{IN} \ge V_{CC} - 0.3V$, or $V_{IN} \le 0.3V$, f = 0	Automotive-A		10			1
		$V_{\rm IN} \ge 0.5V, I = 0$	Automotive -E				15	1

2. V_{IL} (min) = -2.0V for pulse durations of less than 20 ns.



Capacitance

Tested initially and after any design or process changes that may affect these parameters.

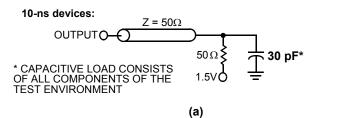
Parameter	Description	Test Conditions	Мах	Unit
C _{IN}	Input Capacitance	$T_A = 25^{\circ}C$, f = 1 MHz, $V_{CC} = 3.3V$	8	pF
C _{OUT}	Output Capacitance		8	pF

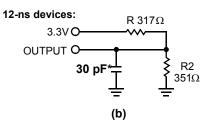
Thermal Resistance

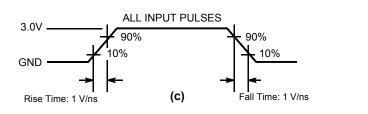
Tested initially and after any design or process changes that may affect these parameters.

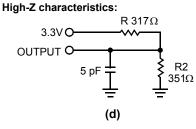
Parameter	Description	Test Conditions	TSOP II	TQFP	VFBGA	Unit
Θ_{JA}		Still Air, soldered on a 3 × 4.5 inch, four-layer printed circuit board	44.56	42.66	46.98	°C/W
Θ_{JC}	Thermal Resistance (Junction to Case)		10.75	14.64	9.63	°C/W

Figure 4. AC Test Loads and Waveforms ^[3]









Note

3. AC characteristics (except High-Z) for 10-ns parts are tested using the load conditions shown in Figure 4 (a). All other speeds are tested using the Thevenin load shown in Figure 4 (b). High-Z characteristics are tested for all speeds using the test load shown in Figure 4 (d).



Switching Characteristics

Over the Operating Range [4]

Demonster	Description	-10		-12		l lucit	
Parameter	Description	Min	Max	Min	Max	Unit	
Read Cycle	<u>.</u>			•	•		•
t _{power} ^[5]	V _{CC} (Typical) to the First Access		1		1		μS
t _{RC}	Read Cycle Time		10		12		ns
t _{AA}	Address to Data Valid			10		12	ns
t _{OHA}	Data Hold from Address Change		3		3		ns
t _{ACE}	CE LOW to Data Valid			10		12	ns
t _{DOE}	OE LOW to Data Valid	Industrial/Automotive-A		5		6	ns
		Automotive-E				8	
t _{LZOE}	OE LOW to Low Z ^[6]		0		0		ns
t _{HZOE}	OE HIGH to High Z ^[6, 7]			5		6	ns
t _{LZCE}	CE LOW to Low Z ^[6]		3		3		ns
t _{HZCE}	CE HIGH to High Z ^[6, 7]			5		6	ns
t _{PU}	CE LOW to Power Up		0		0		ns
t _{PD}	CE HIGH to Power Down			10		12	ns
t _{DBE}	Byte Enable to Data Valid	Industrial/Automotive-A		5		6	ns
		Automotive-E				8	
t _{LZBE}	Byte Enable to Low Z		0		0		ns
t _{HZBE}	Byte Disable to High Z			5		6	ns
Write Cycle ^{[8,}	9]				•		•
t _{WC}	Write Cycle Time		10		12		ns
t _{SCE}	CE LOW to Write End		7		8		ns
t _{AW}	Address Setup to Write End		7		8		ns
t _{HA}	Address Hold from Write End		0		0		ns
t _{SA}	Address Setup to Write Start		0		0		ns
t _{PWE}	WE Pulse Width	7		8		ns	
t _{SD}	Data Setup to Write End	5		6		ns	
t _{HD}	Data Hold from Write End	0		0		ns	
t _{LZWE}	WE HIGH to Low Z ^[6]		3	1	3		ns
t _{HZWE}	WE LOW to High Z ^[6, 7]			5		6	ns
t _{BW}	Byte Enable to End of Write		7		8		ns

Notes

4. Test conditions assume signal transition time of 3 ns or less, timing reference levels of 1.5V, and input pulse levels of 0 to 3.0V.

5.

6.

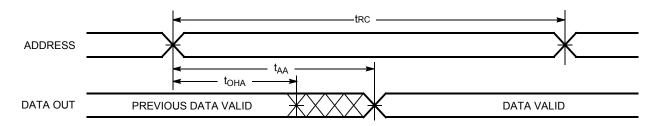
 t_{POWER} gives the minimum amount of time that the power supply is at typical V_{CC} values until the first memory access is performed. At any temperature and voltage condition, t_{HZCE} is less than t_{LZCE} , t_{HZOE} is less than t_{LZOE} , and t_{HZWE} is less than t_{LZWE} for any device. t_{HZOE} , t_{HZBE} , t_{HZCE} , and t_{HZWE} are specified with a load capacitance of 5 pF as in part (d) of "AC Test Loads and Waveforms ^[3]" on page 5. Transition is measured ±500 mV from steady state voltage. 7.

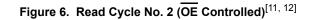
The internal write time of the memory is defined by the overlap of CE LOW, WE LOW, and BHE/BLE LOW. CE, WE, and BHE/BLE must be LOW to initiate a write. The transition of these signals terminate the write. The input data setup and hold timing is referenced to the leading edge of the signal that terminates the write.
 The minimum write cycle time for Write Cycle No. 3 (WE controlled, OE LOW) is the sum of t_{HZWE} and t_{SD}.

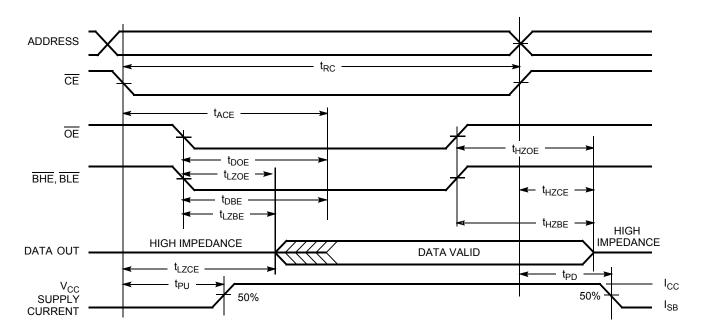


Switching Waveforms









Notes

10. Device is continuously selected. \overline{OE} , \overline{CE} , \overline{BHE} , and/or $\overline{BLE} = V_{IL}$. 11. WE is HIGH for read cycle.

12. Address valid prior to or coincident with \overline{CE} transition LOW.



Switching Waveforms (continued)

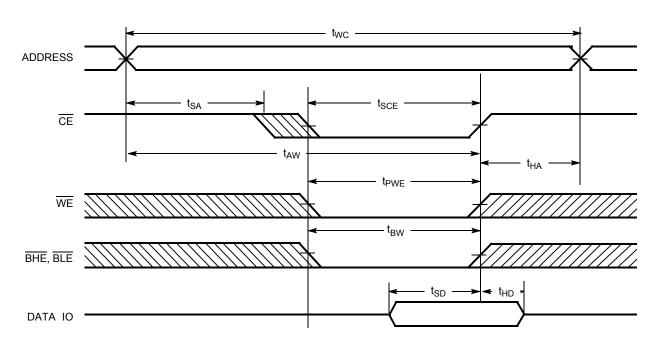
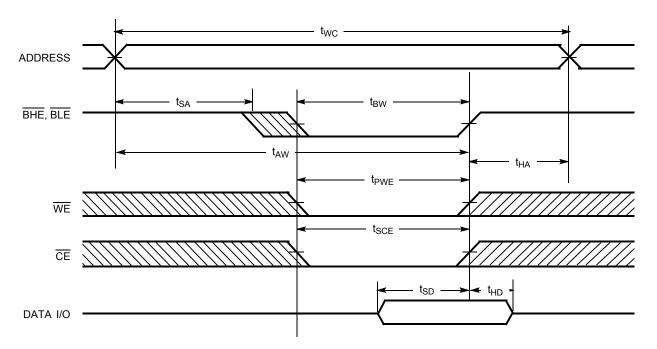


Figure 7. Write Cycle No. 1 (CE Controlled)^[13, 14]

Figure 8. Write Cycle No. 2 (BLE or BHE Controlled)



Notes 13. Data I/O is high impedance if \overline{OE} , \overline{BHE} , and/or $\overline{BLE} = V_{IH}$. 14. If \overline{CE} goes HIGH simultaneously with WE going HIGH, the output remains in a high impedance state.



Switching Waveforms (continued)

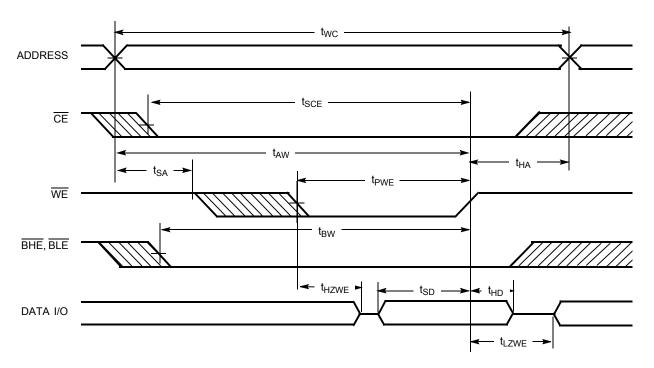


Figure 9. Write Cycle No. 3 (WE Controlled, LOW)

Truth Table

CE	OE	WE	BLE	BHE	I/O ₀ -I/O ₇	I/O ₈ – I/O ₁₅	Mode	Power
Н	Х	Х	Х	Х	High Z	High Z	Power Down	Standby (I _{SB})
L	L	Н	L	L	Data Out	Data Out	Read – All Bits	Active (I _{CC})
L	L	Н	L	Н	Data Out	High Z	Read – Lower Bits Only	Active (I _{CC})
L	L	Н	Н	L	High Z	Data Out	Read – Upper Bits Only	Active (I _{CC})
L	Х	L	L	L	Data In	Data In	Write – All Bits	Active (I _{CC})
L	Х	L	L	Н	Data In	High Z	Write – Lower Bits Only	Active (I _{CC})
L	Х	L	Н	L	High Z	Data In	Write – Upper Bits Only	Active (I _{CC})
L	Н	Н	Х	Х	High Z	High Z	Selected, Outputs Disabled	Active (I _{CC})

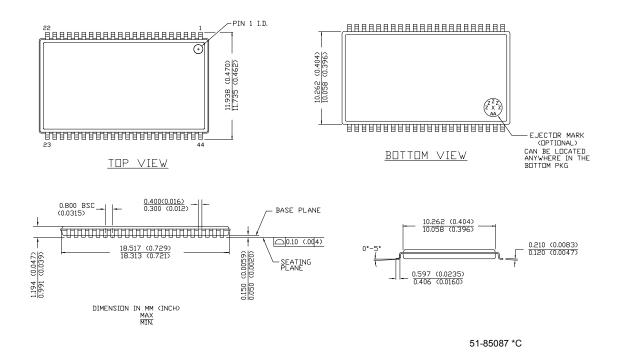


Ordering Information

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
10	CY7C1011CV33-10BVI	51-85150	48-ball (6 x 8 x 1 mm) VFBGA	Industrial
	CY7C1011CV33-10ZSXA	51-85087	44-pin TSOP II (Pb-Free)	Automotive-A
12	CY7C1011CV33-12AXI	51-85064	44-pin TQFP (Pb-Free)	Industrial
	CY7C1011CV33-12ZSXE	51-85087	44-pin TSOP II (Pb-Free)	Automotive-E

Package Diagrams

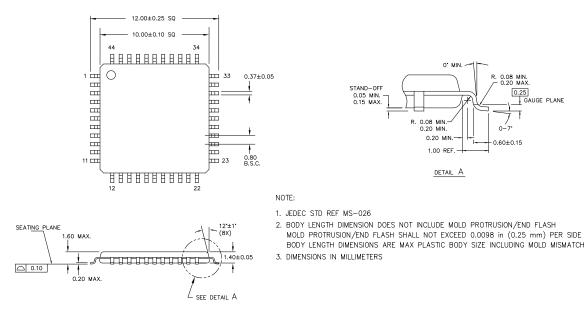






Package Diagrams (continued)

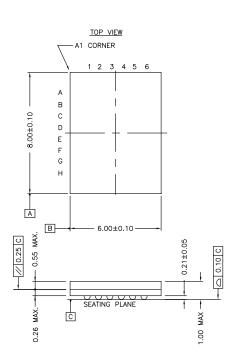


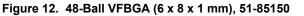


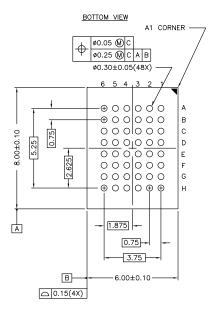
51-85064 *D



Package Diagrams (continued)







51-85150 *E



Document History Page

	Document Title: CY7C1011CV33, 2-Mbit (128K x 16) Static RAM Document Number: 38-05232							
REV.	ECN NO.	Issue Date	Orig. of Change	Description of Change				
**	117132	07/31/02	HGK	New Data Sheet				
*A	118057	08/19/02	HGK	Pin configuration for 48-ball FBGA correction				
*B	119702	10/11/02	DFP	Updated FBGA to VFBGA; updated package code on page 8 to BV48A. Updated address pinouts on page 1 to A0 to A16. Updated CMOS standby current on page 1 from 8 to 10 mA				
*C	386106	See ECN	PCI	Added lead-free parts in Ordering Information Table				
*D	498501	See ECN	NXR	Corrected typo in the Logic Block Diagram on page# 1 Included the Maximum Ratings for Static Discharge Voltage and Latch up Current on page# 3 Changed the description of I _{IX} from Input Load Current to Input Leakage Current in DC Electrical Characteristics table Updated the Ordering Information Table				
*E	522620	See ECN	VKN	Added Thermal Resistance Table				
*F	1891366	See ECN	VKN/AESA	Added -10ZSXA part Updated Ordering Information table				
*G	2428606	See ECN	VKN/PYRS	Corrected typo in the 44-Pin TSOP and 48-Ball FBGA pinout Removed Commercial parts Removed 15 ns speed bin Removed inactive parts from the Ordering Information table				
*H	2664421	02/25/09	VKN/AESA	Added Automotive-E specs for 12 ns speed Updated Ordering Information table				
*	2898399	03/24/2010	KAO/AJU	Updated Package Diagrams				

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